## Application/Control No. Applicant(s)/Patent Under Reexamination DUCROS ET AL. Examiner Patrick D. Niland Applicant(s)/Patent Under Reexamination DUCROS ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5344635	09-1994	Bujard et al.	
	В	US-3653959	04-1972	Kehr et al.	
	С	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

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	Ν					
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## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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